

#37787 + #37793

Measurement:	TERS:	Tip-in spectrum
	Raman:	Tip-out spectrum, taken at the same spot without the impact of the tip
System:	Renishaw inVia Raman spectrometer	
Additional setup:	MultiView 2000 (Nanonics Imaging Ltd, Jerusalem, Israel)	
Measurement geometry:	Backscattering - incident beam linearly polarized - scattered light not restricted in terms of polarization	
Objective:	Nikon LD 50x/0.45	
Grating:	2400 l/mm	
Nominal resolution:	1.13 cm ⁻¹	
Slit width:	65 µm	
Collection mode:	stat:	fixed grating position, grating moves discretely to expand measurement range
File labeling:	<i>Sample name _ measurement _ layer – measurement number _ laser wavelength _ collection mode _ exposure time _ laser power.txt</i>	

#33167

Measurement:	TERS:	Tip-in spectrum
	Raman:	Tip-out spectrum, taken at the same spot without the impact of the tip
System:	Renishaw inVia Raman spectrometer	
Additional setup:	MultiView 2000 (Nanonics Imaging Ltd, Jerusalem, Israel)	
Measurement geometry:	Backscattering - incident beam linearly polarized - scattered light not restricted in terms of polarization	
Objective:	Nikon LD 50x/0.45	
Grating:	2400 + 1800 l/mm	
Nominal resolution:	1.13 – 1.5 cm ⁻¹	
Slit width:	65 µm	
Collection mode:	stat:	fixed grating position, grating moves discretely to expand measurement range
File labeling:	<i>Sample name _ measurement _ TERS tip _ layer – measurement number _ laser wavelength _ grating _ collection mode _ exposure time _ laser power.txt</i>	